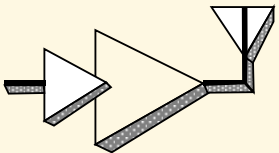


A Testbench for Analysis of Bias Network Effects in an RF Power Amplifier with DPD

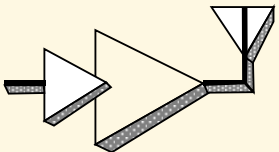
Marius Ubostad and Morten Olavsbråten

Dept. of Electronics and Telecommunications
Norwegian University of Science and Technology



Outline

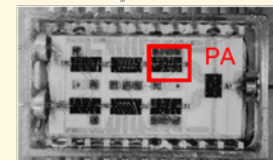
- Introduction
 - Motivation
 - Bias Network design
 - DPD
- Measurement Setup
- Experimental Results
- Conclusions



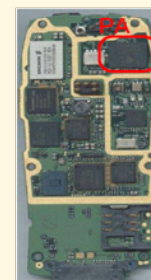
Introduction

- The power amplifier is a critical component in a wireless system
- Important power amplifier parameters:
 - Frequency band
 - Power
 - Bandwidth
 - Linearity
 - Efficiency
 - Size, cost ...
- Linearity vs. efficiency tradeoff
- Linearization, efficiency enhancement

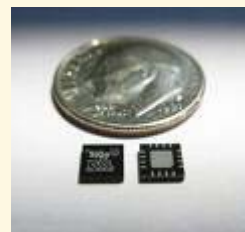
Satellite transmissions



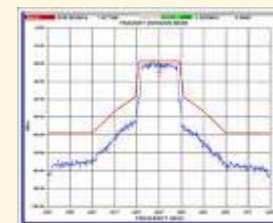
Cellular phones



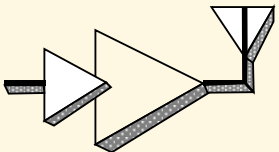
Handset transmitters



Size, cost

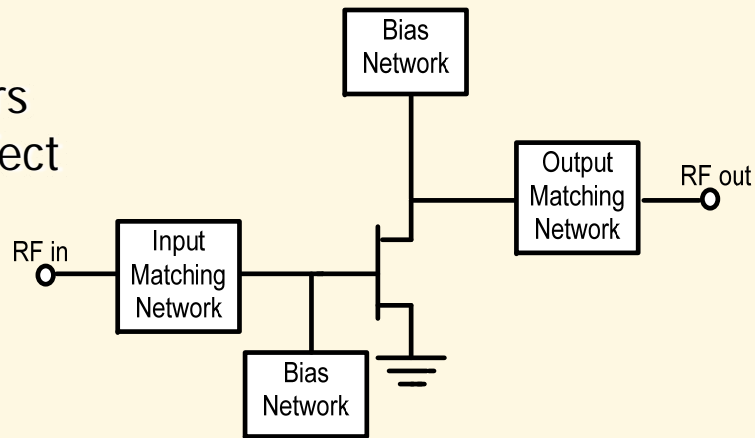
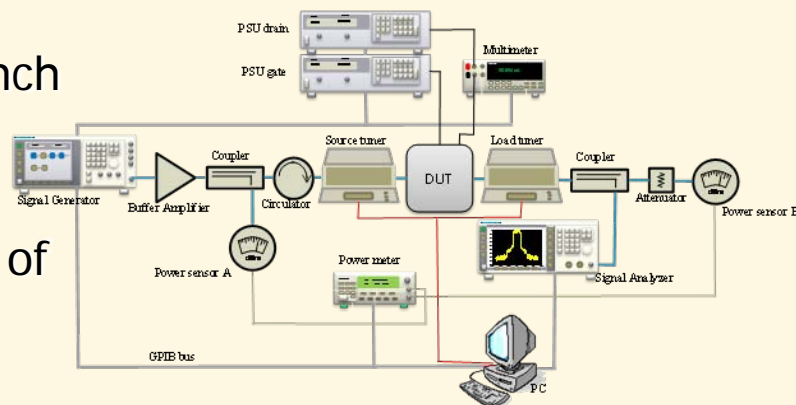


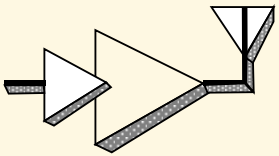
Spectral mask



Introduction

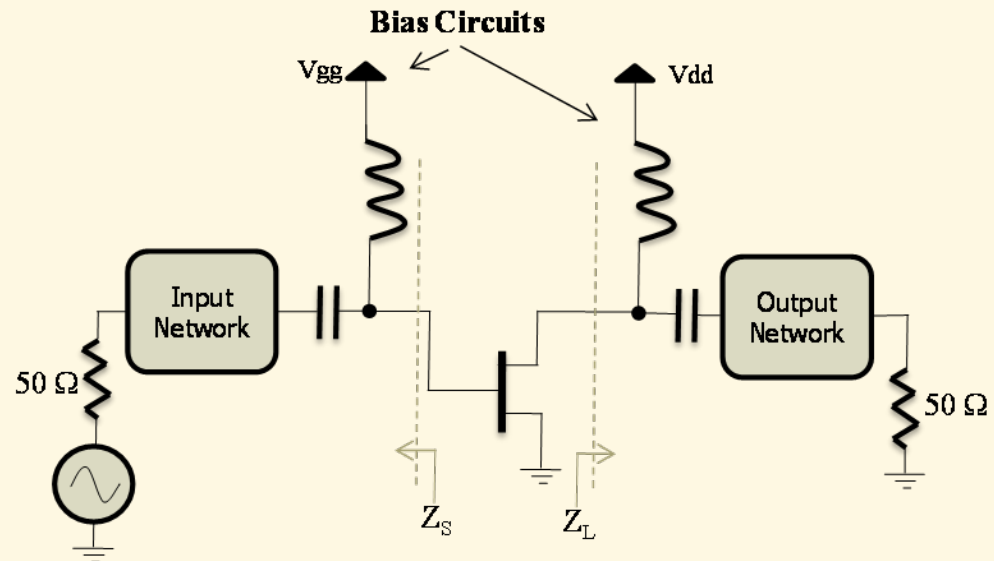
- The scope of this work is to build a testbench where we can do most measurements necessary for a PA design
- In addition we want to measure the effect of different bias network in the PA
- A power amplifier based on a pHEMT transistor is designed for the experiments
- A standard bias network is first used for the experiments
- Two extreme variants where large inductors are used are tested to demonstrate the effect on the linearity
- The measurements are done with and without DPD

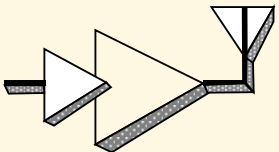




Introduction

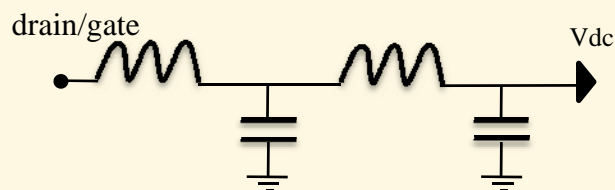
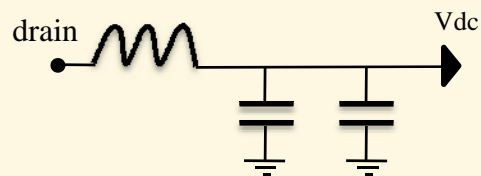
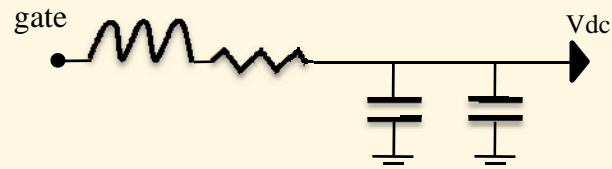
- Bias network design
 - Isolate RF from DC
 - Important for stability at low frequencies
 - Defines the impedance at baseband
 - Often based on empirical design methods
 - More critical as the bandwidth of the signal increases
 - Traditionally simplified to a large inductor in text books, but recently this topic is being covered (Cripps)

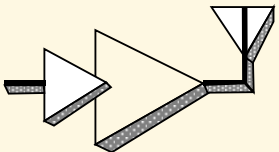




Introduction

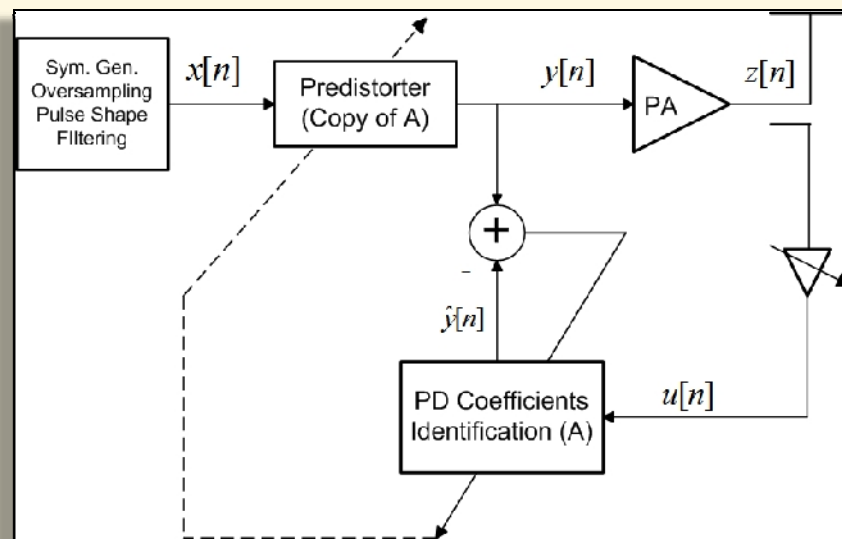
- Different bias configurations
 - Resistor improve stability, but not desirable at drain
 - Large impedance at baseband can result in drain modulation/memory effects
 - Internal parasitics in SMD components



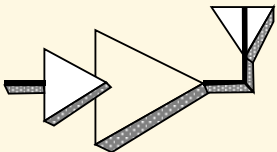


Introduction

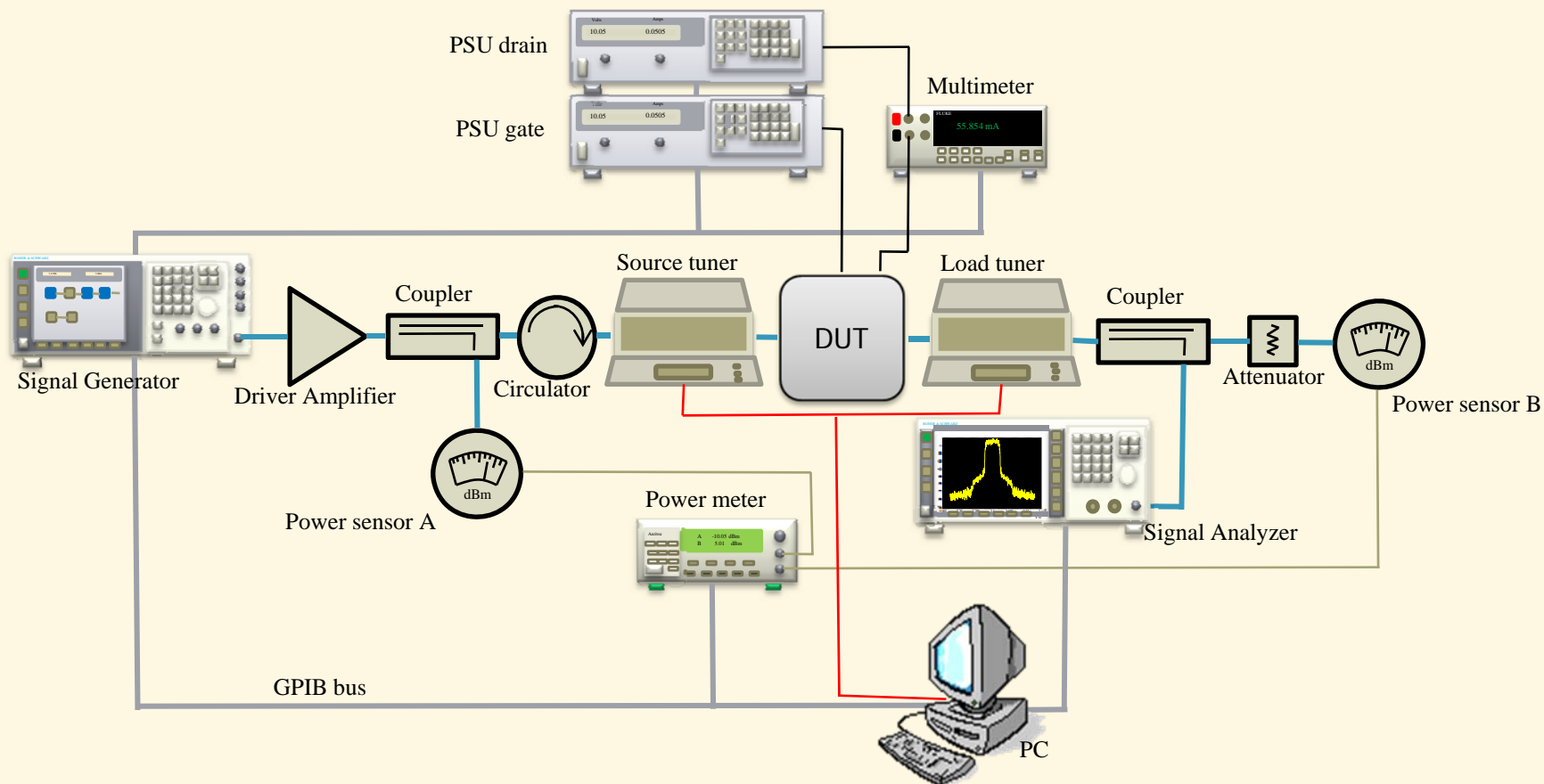
- Simple memoryless DPD
 - Complex baseband samples at the input and output are recorded
 - A blockbased least square algorithm is applied to identify the DPD coefficients
 - The DPD algorithm and communication with the instruments is implemented in Matlab
 - The algorithm sensitive to memory that has its origin in the bias network

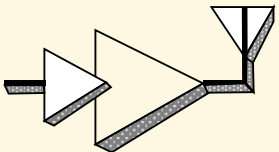


The baseband DPD model based on indirect learning architecture



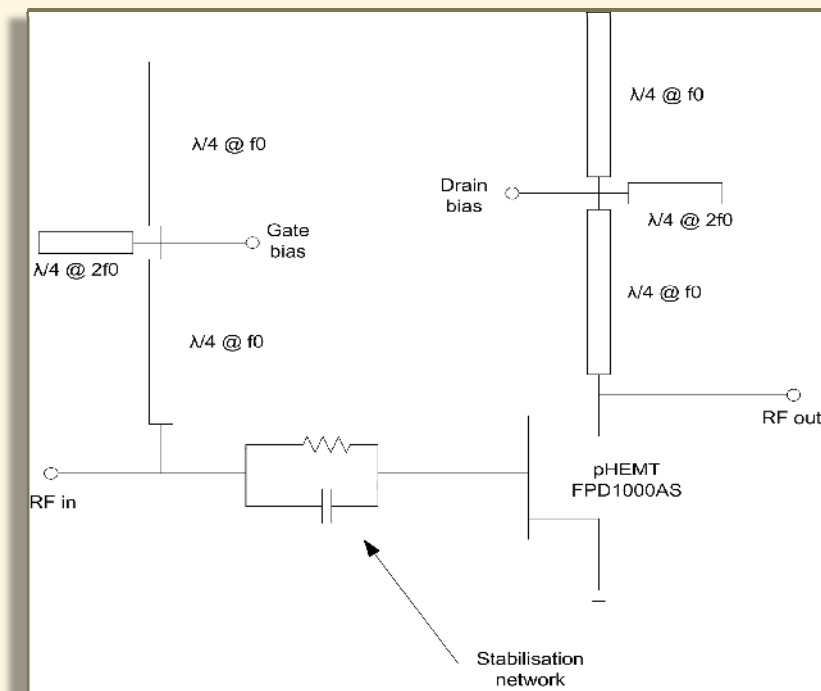
Measurement Setup



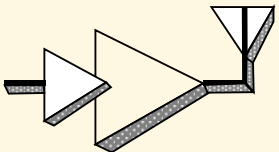


Measurement Setup

- Combinations of quarter-wavelength transmission lines isolates bias circuitry from RF at f_0 and $3f_0$, $2f_0$ shorted
- A 1 watt pHEMT transistor used in the experiments
- The transistor is biased in deep class AB
- 2.4 Ghz



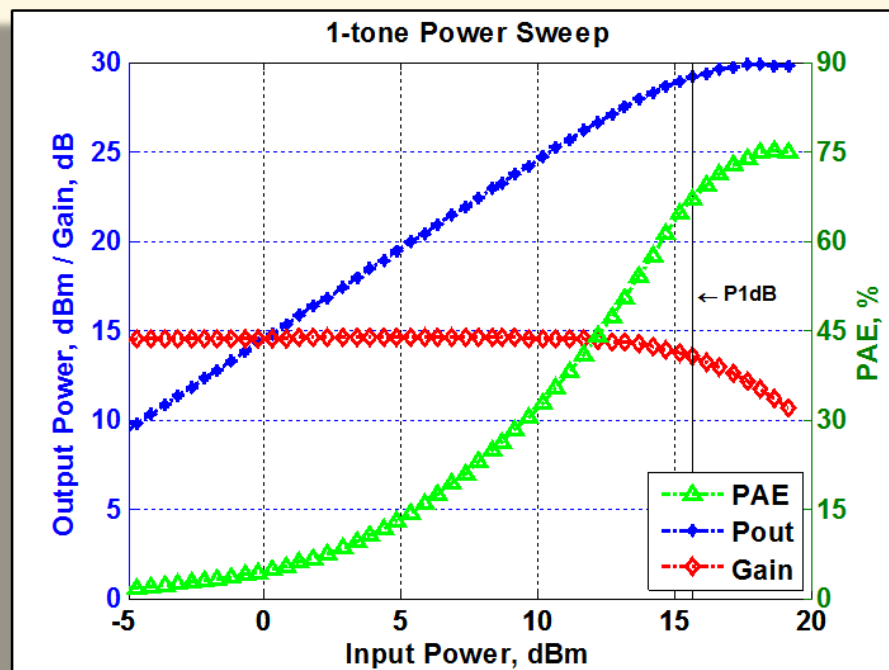
DUT

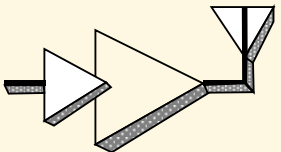


Experimental Results

- 1-tone measurements
 - Source- and load impedance optimized for best efficiency
 - 1-tone measurements are independent on the bias circuit

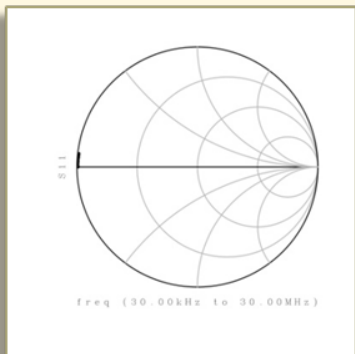
1 dB Compression	
Pout	29.2 dBm
PAE	67 %



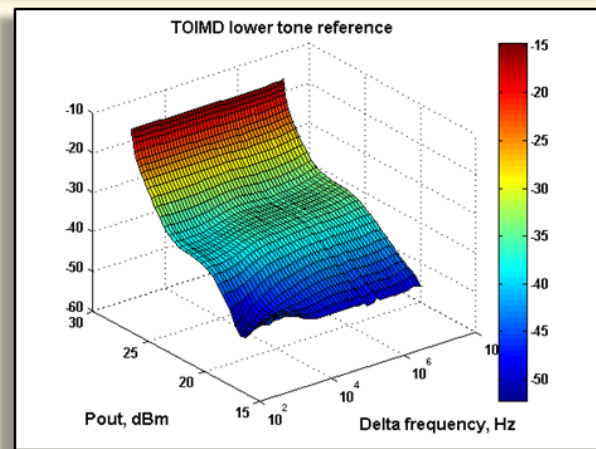
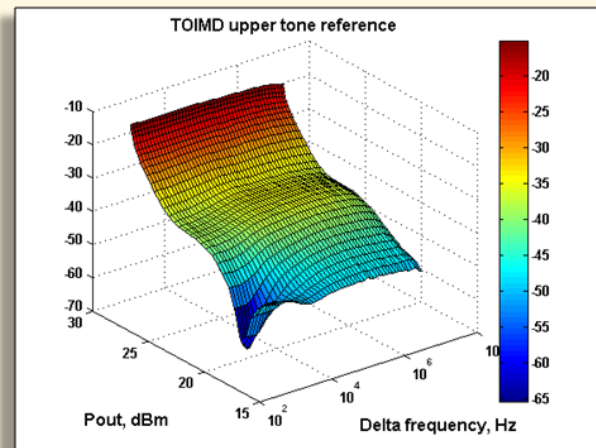
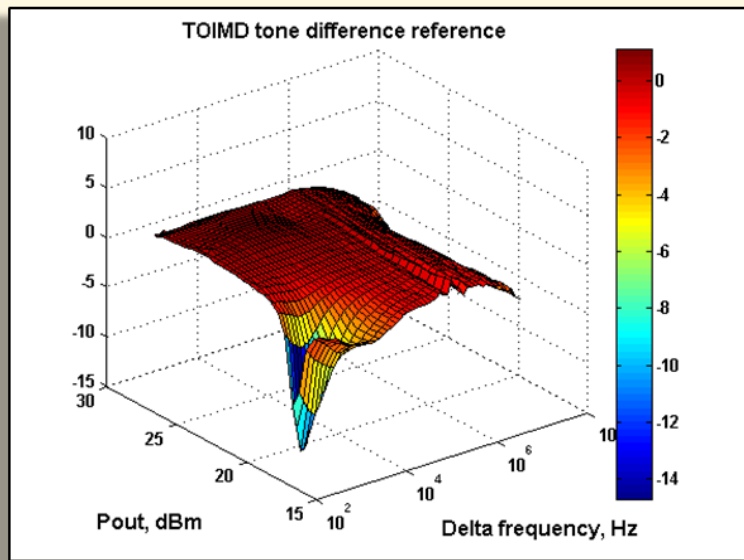


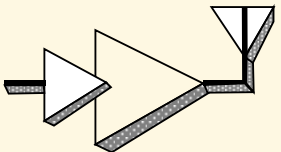
Experimental Results

- 2-tone measurements with reference bias
 - Close to short circuit at baseband at drain
 - Small differences between upper and lower IMD product, except one point



Bias circuit impedance



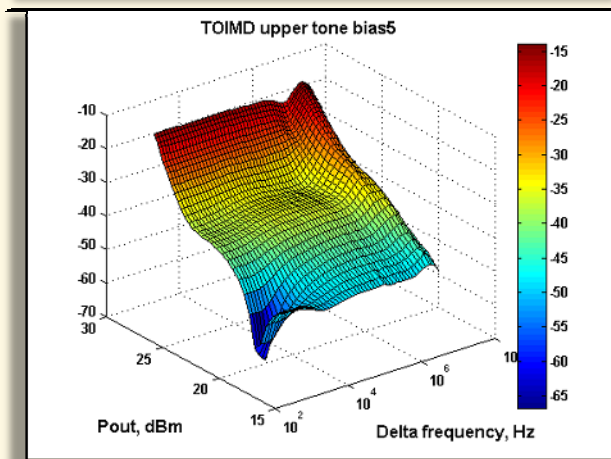
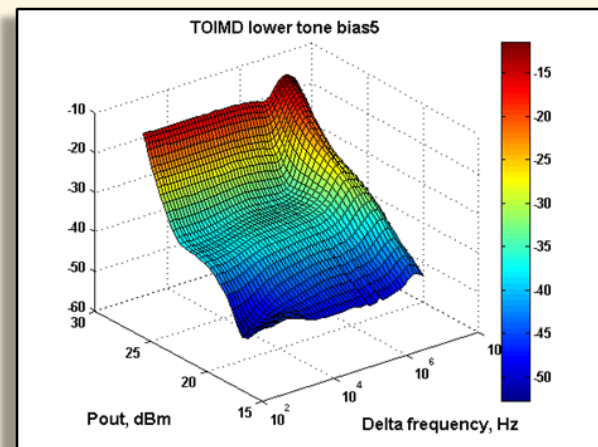
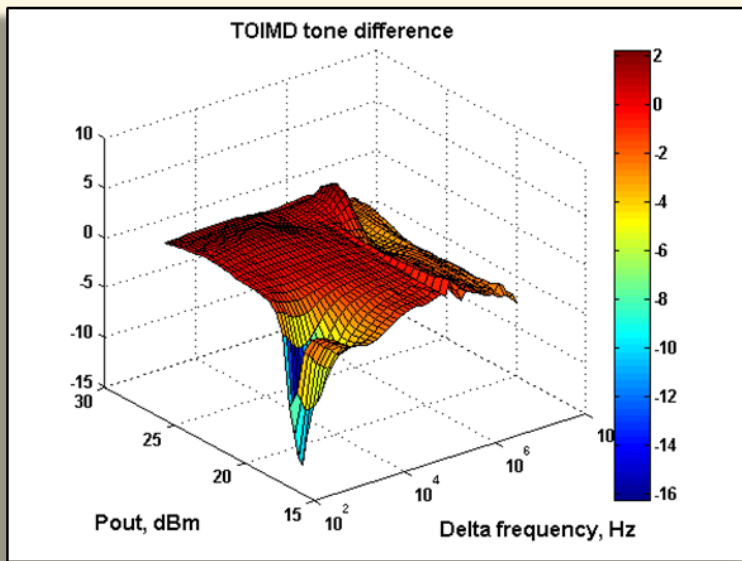


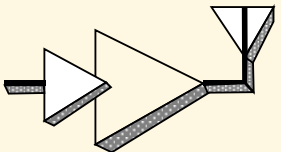
Experimental Results

- 2 tone measurements with large inductor at drain
 - Increasing differens in lower and upper IMD product



Bias circuit impedance drain



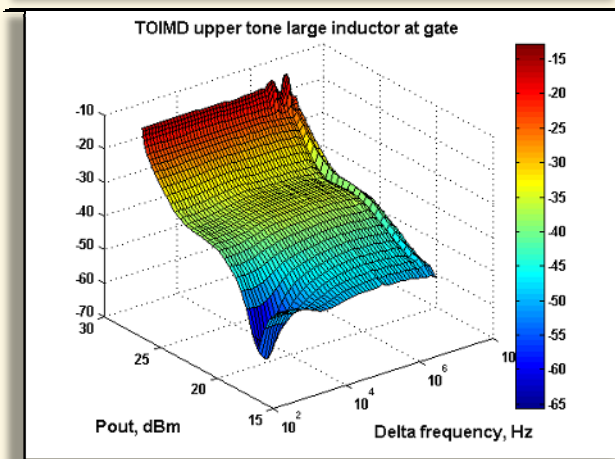
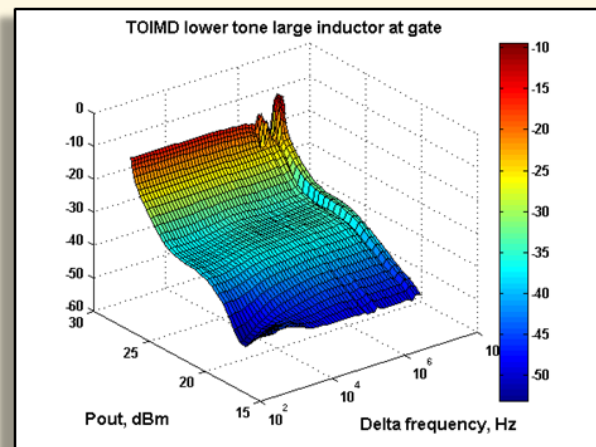
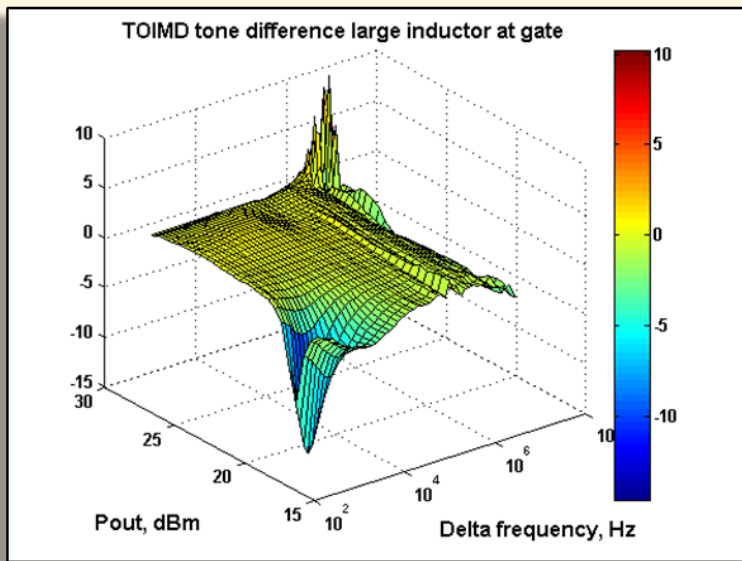


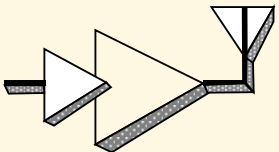
Experimental Results

- 2 tone measurements with large inductor at gate



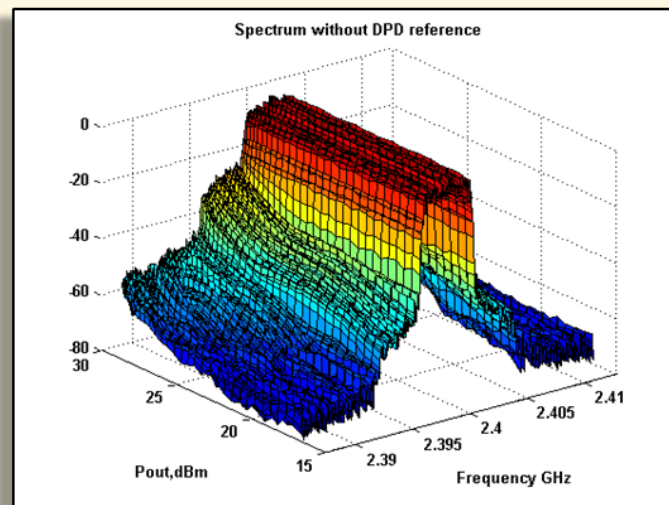
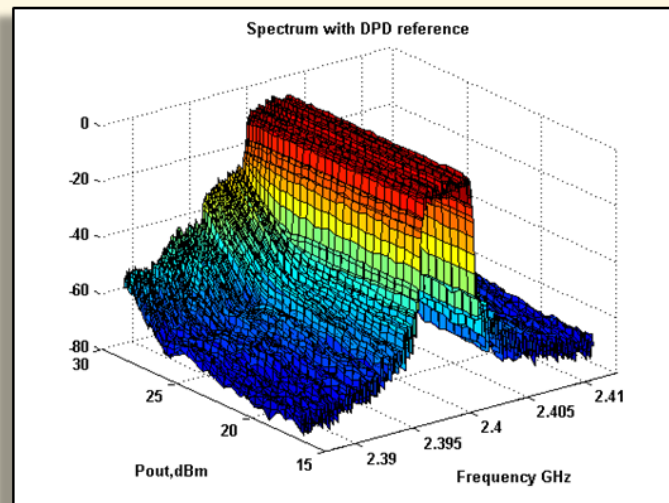
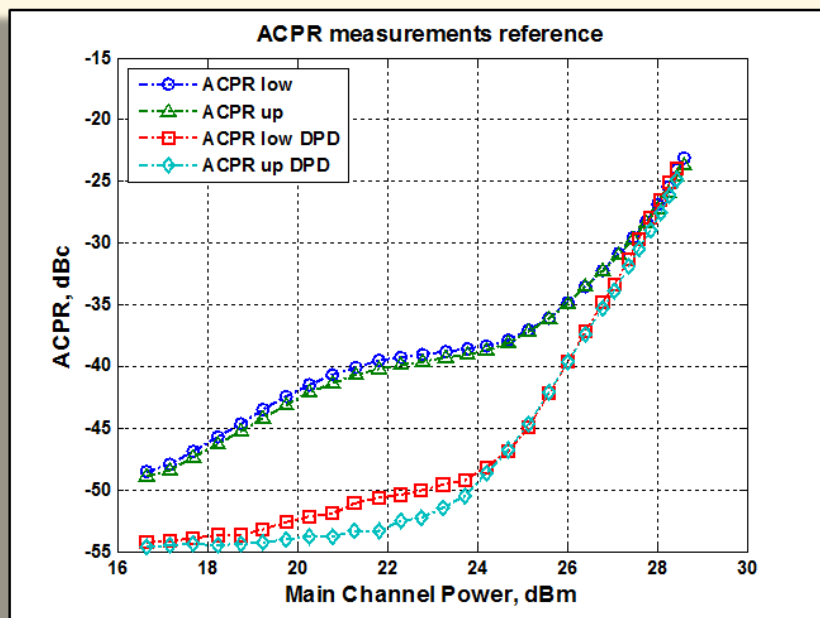
Bias circuit impedance gate

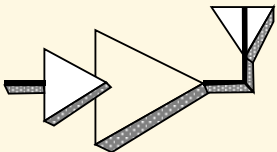




Experimental Results

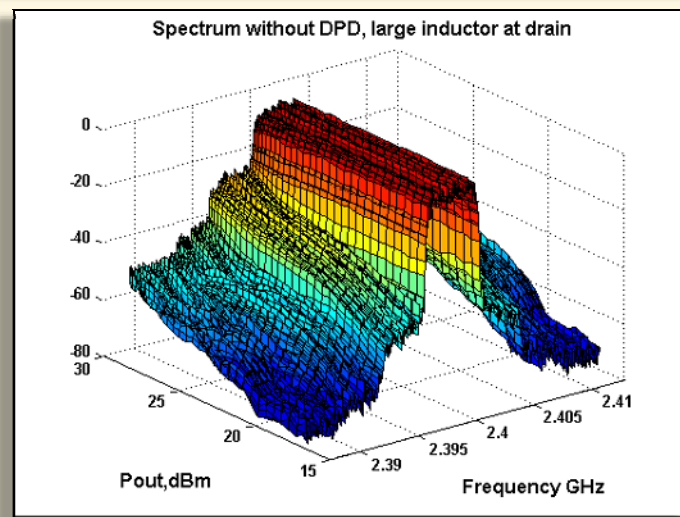
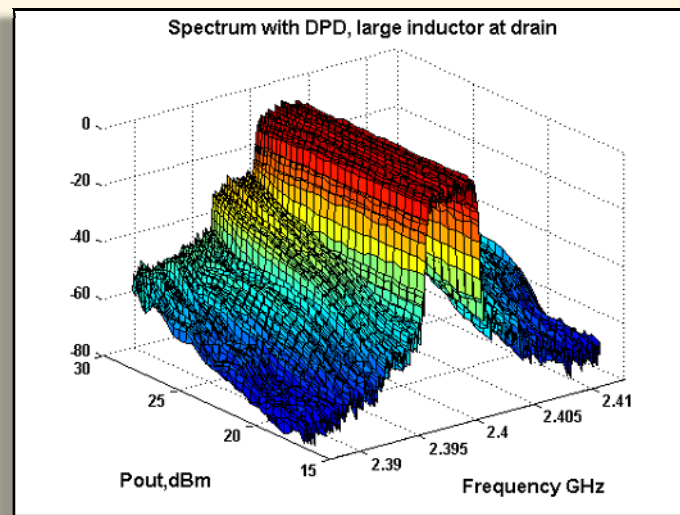
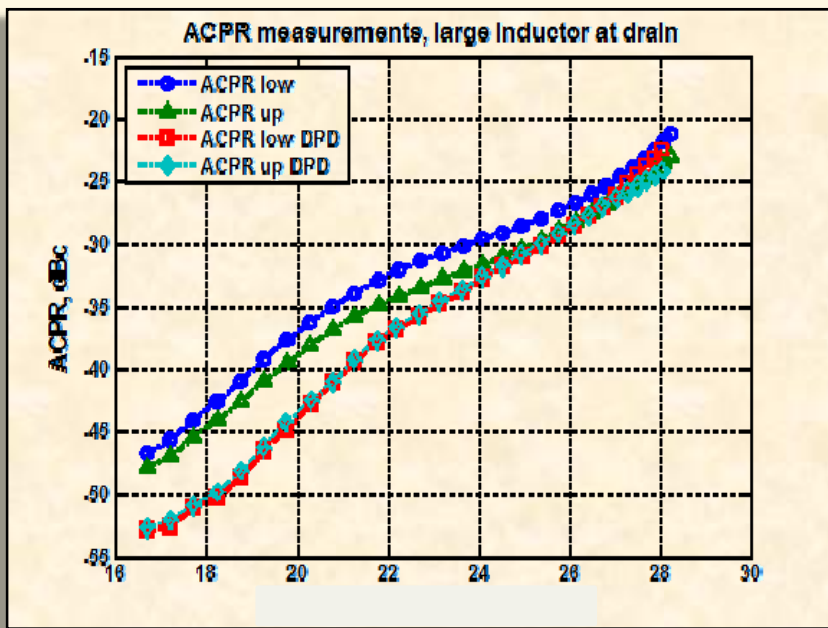
- ACPR measurements with reference bias network
 - 16 QAM, symbolrate 3.84 MHz
 - About 10 dB improvement with DPD

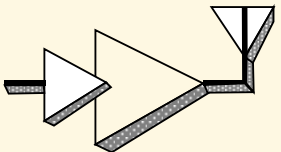




Experimental Results

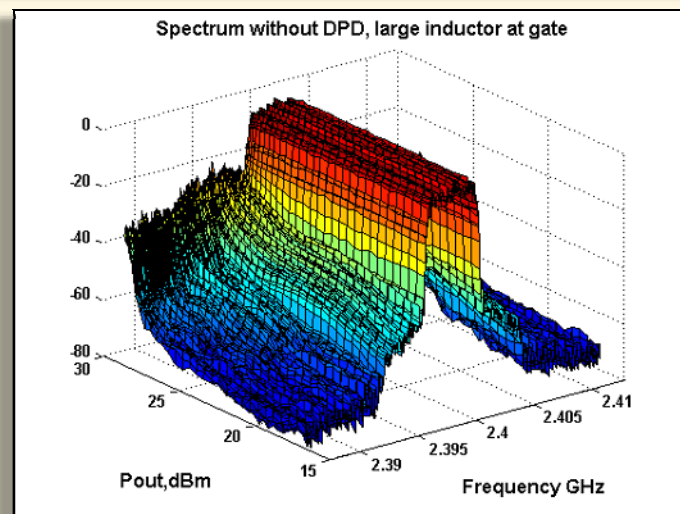
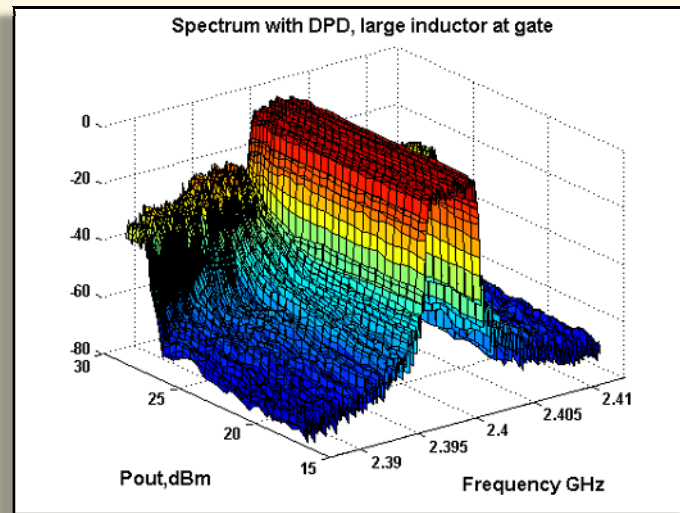
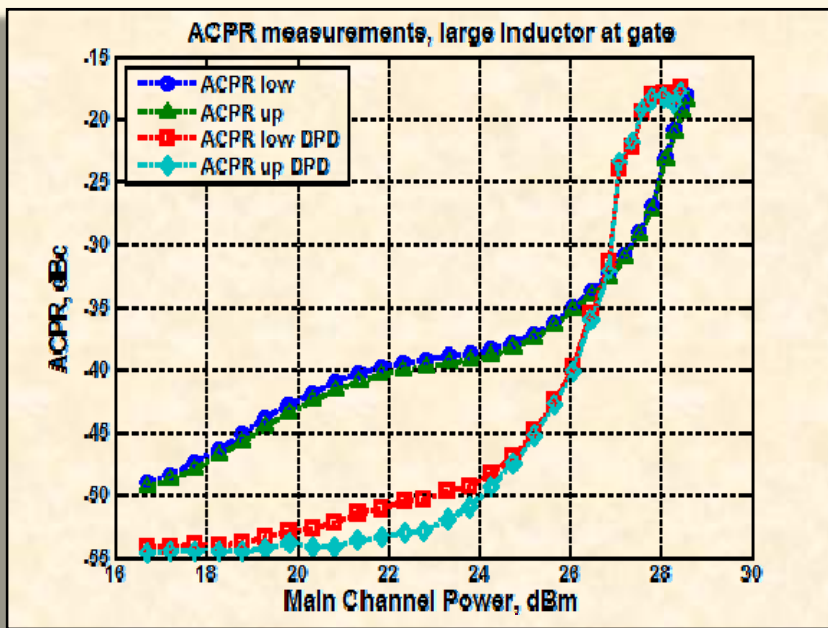
- Linearity measurements with large inductor at drain
 - ACPR degraded
 - DPD not able to compensate due to memory/drain modulation

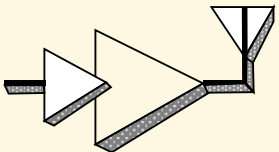




Experimental Results

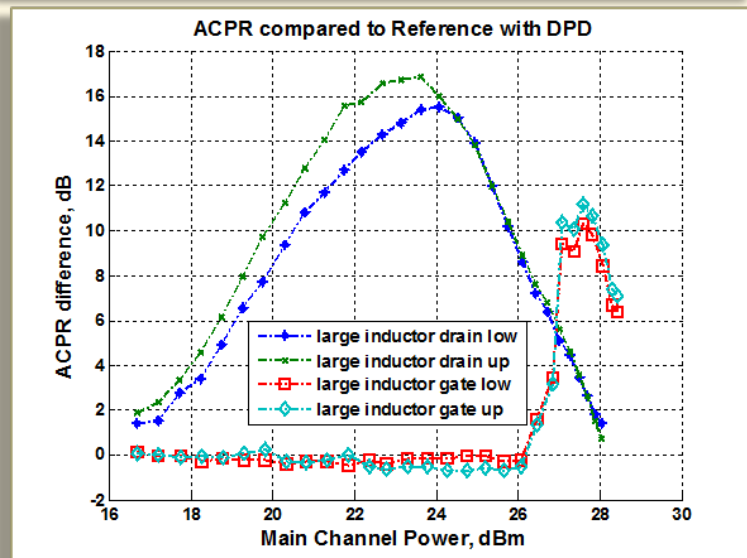
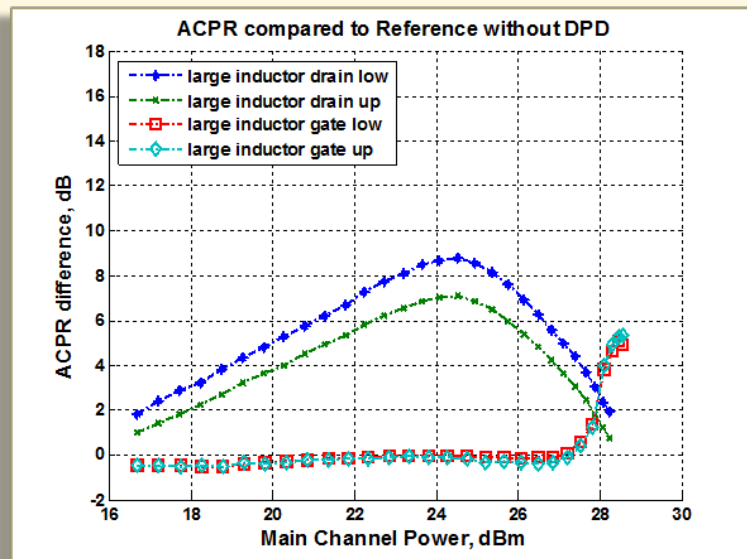
- Linearity measurements with large inductor at gate
 - ACPR unchanged at low power levels
 - At high output power ACPR is drastically degraded

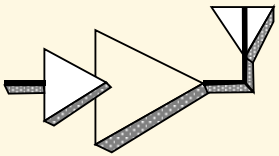




Experimental Results

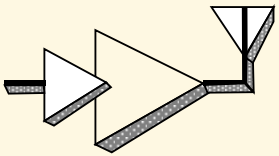
- A large inductance at drain degrades the linearity, DPD cannot compensate for this
- A large inductance at gate doesn't affect the linearity at low power but has a significant impact at high power, gate modulation?





Conclusions

- A testbench for PA design is presented that includes automated measurements
- In addition to load-pull the effect of the bias network can be easily measured
- To demonstrate the importance of the bias circuits two extreme variants are tested and their effect on the linearity are measured
- Measurements show that large inductance at drain degrades the linearity as expected and that a simple memoryless DPD cannot compensate for this
- A large inductance at gate only affects the linearity at high power levels, gate modulation



Acknowledgement

We would like to thank:

- The Research Council of Norway, the research program WIWIC II

Thank you for your attention!